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Figure 1A

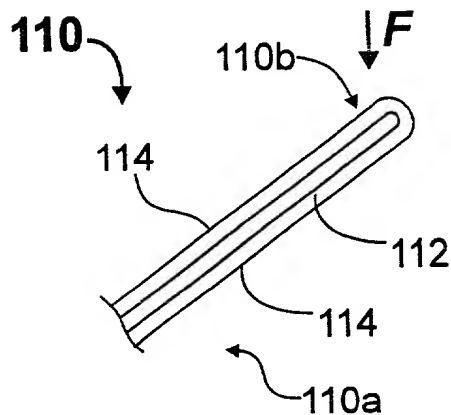


Figure 1B

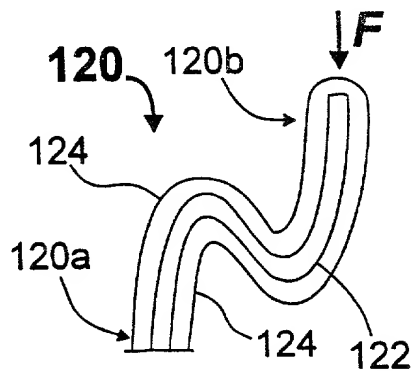


Figure 1C

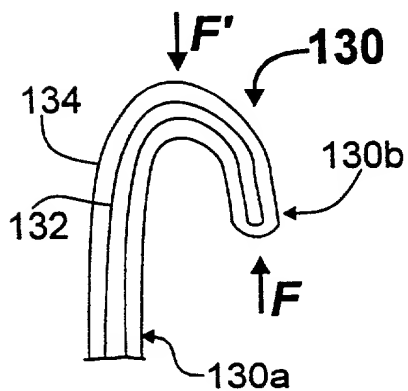


Figure 1D

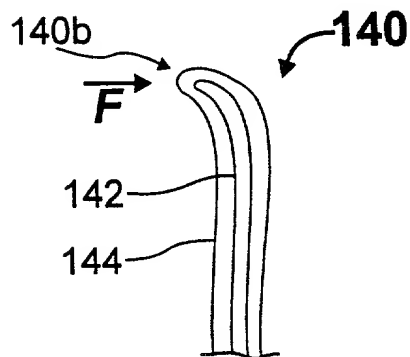


Figure 1E

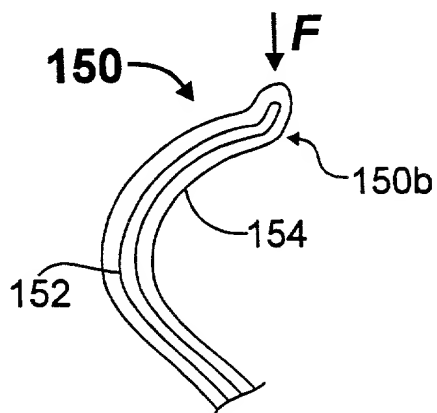


FIG. 1A

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Figure 2A

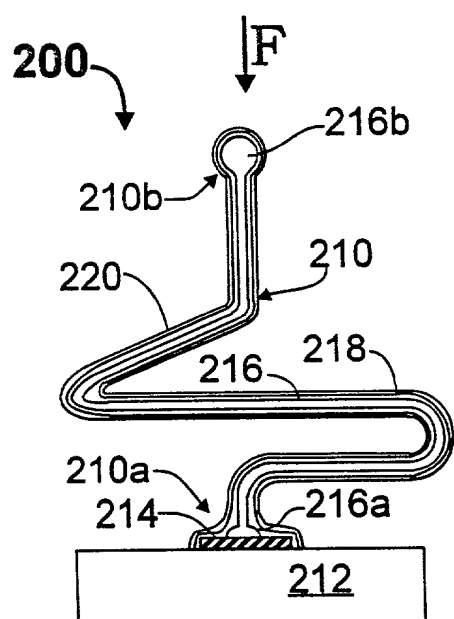
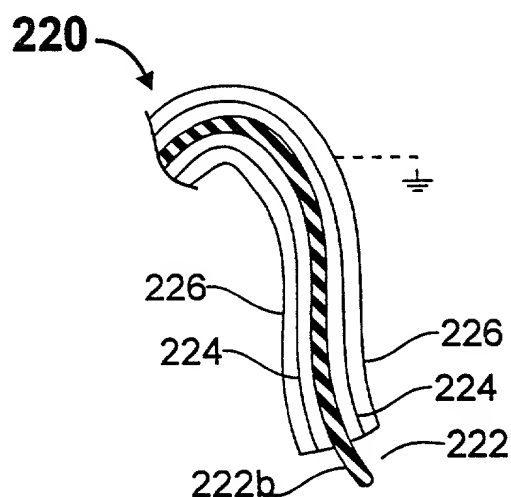
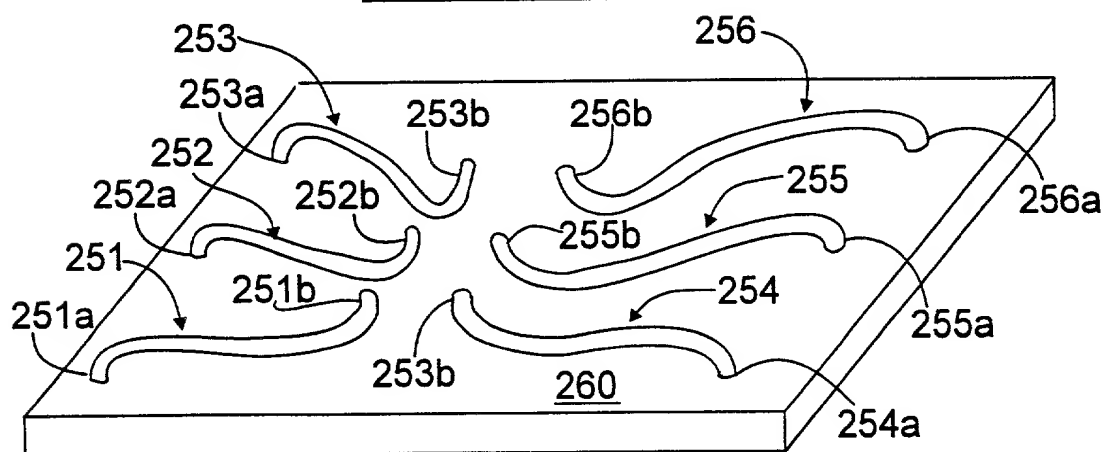


Figure 2B



250

Figure 2C



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Figure 2D

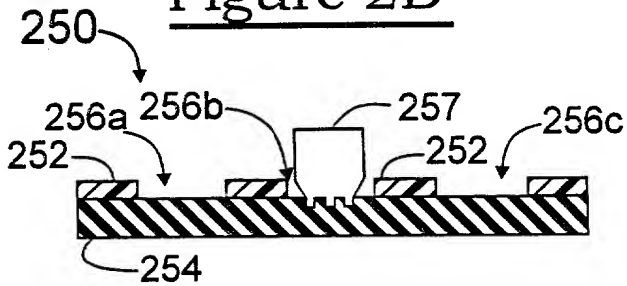


Figure 2E

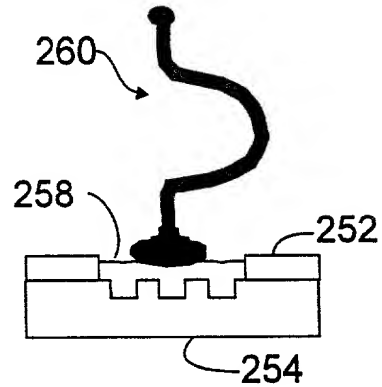


Figure 2F

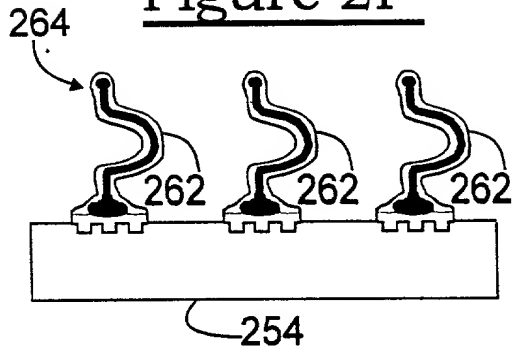


Figure 2G

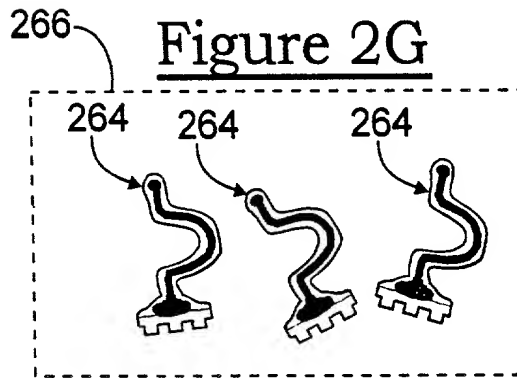


Figure 2H

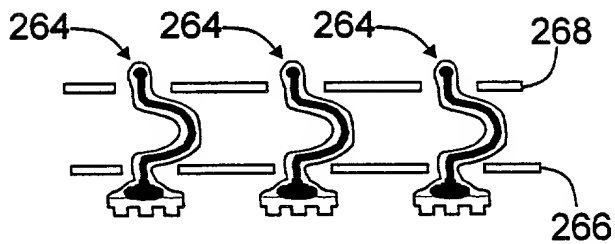
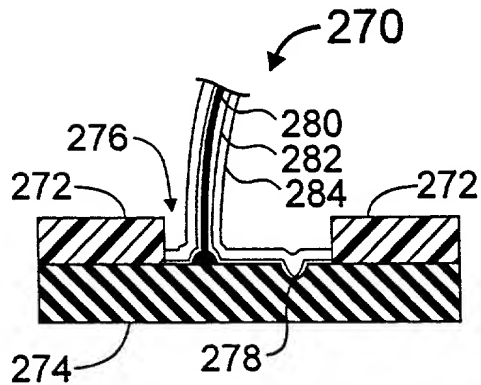
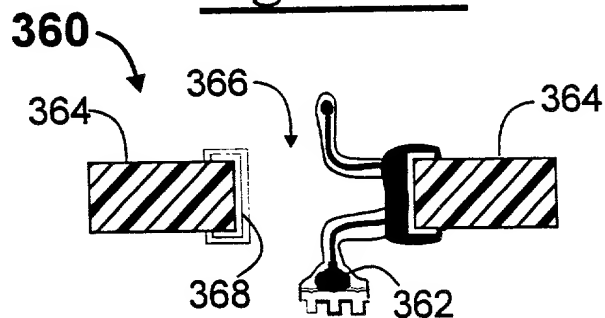


Figure 2I





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Figure 4

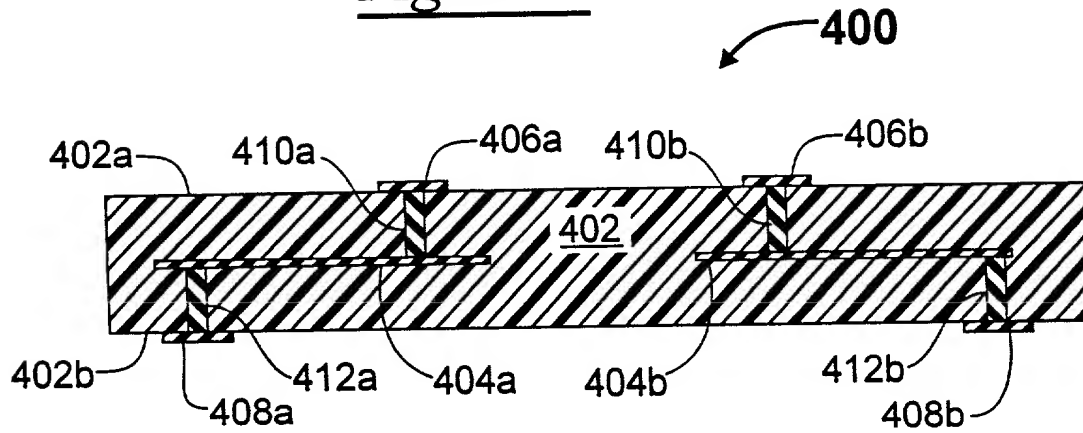
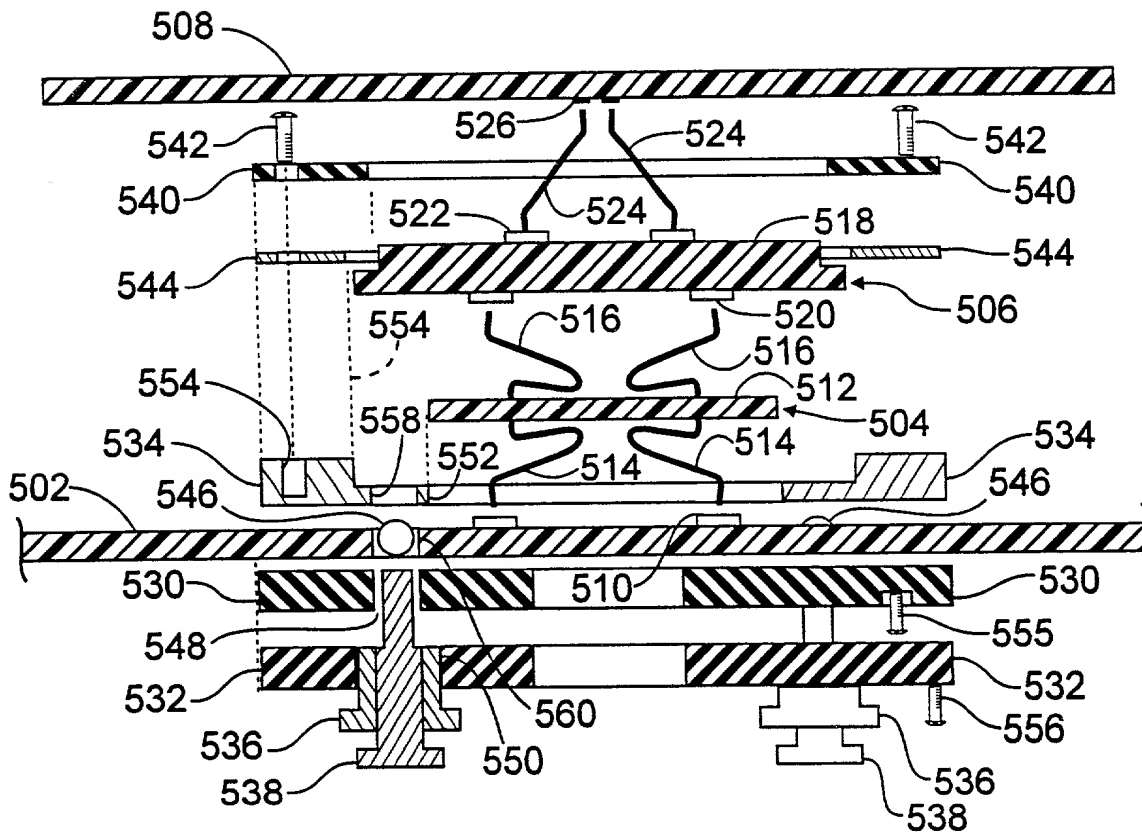


FIG. 4 is a cross-sectional view of the probe card assembly 400.

500



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Figure 5A

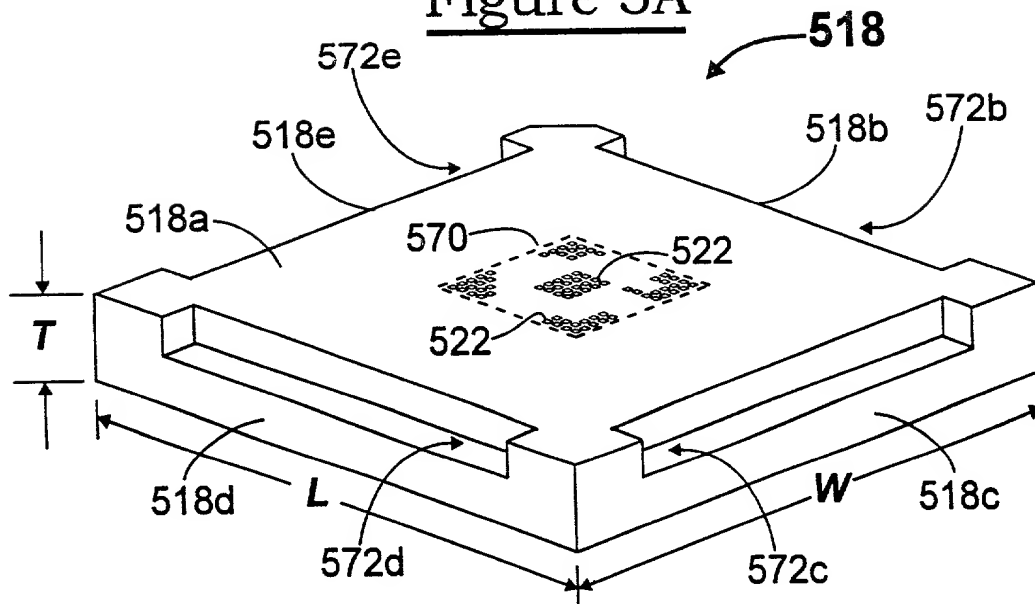
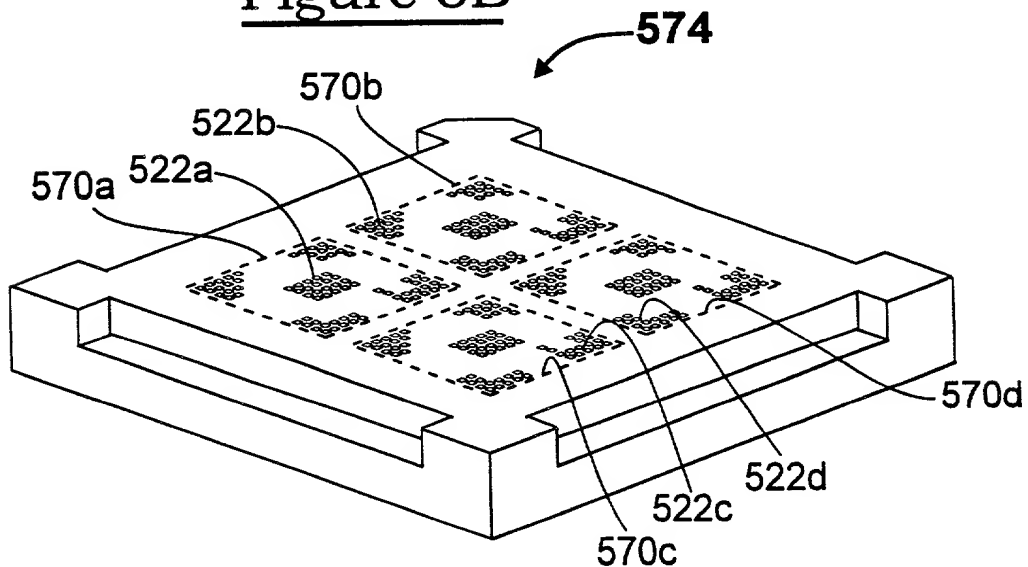


Figure 5B



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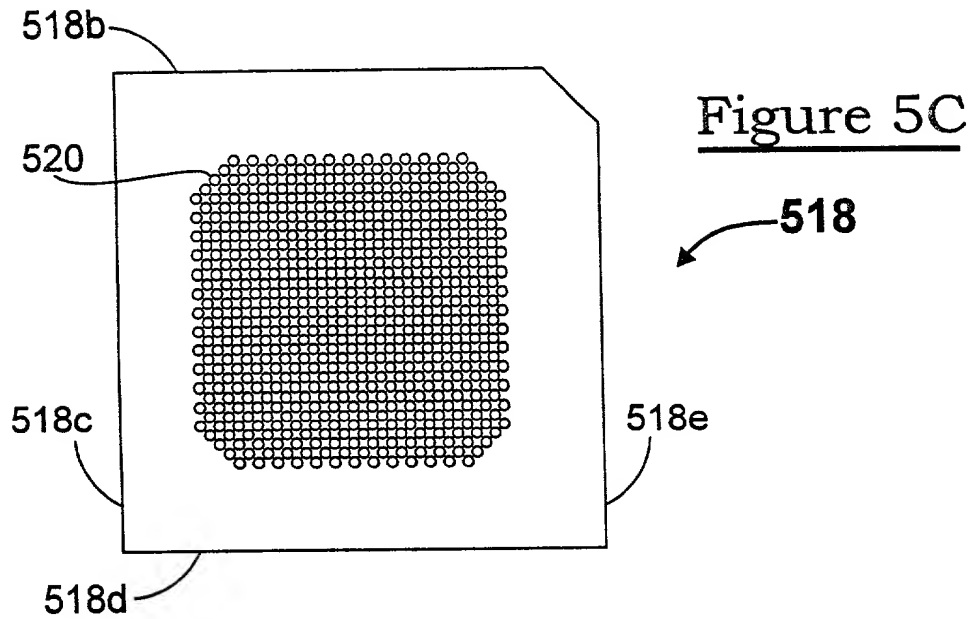


Figure 6A

580

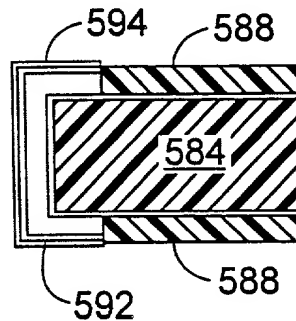
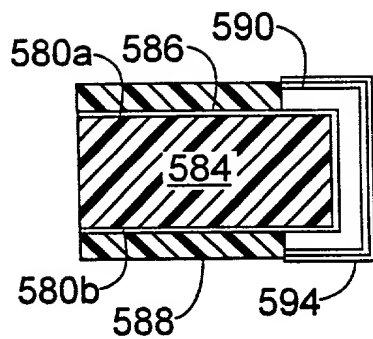
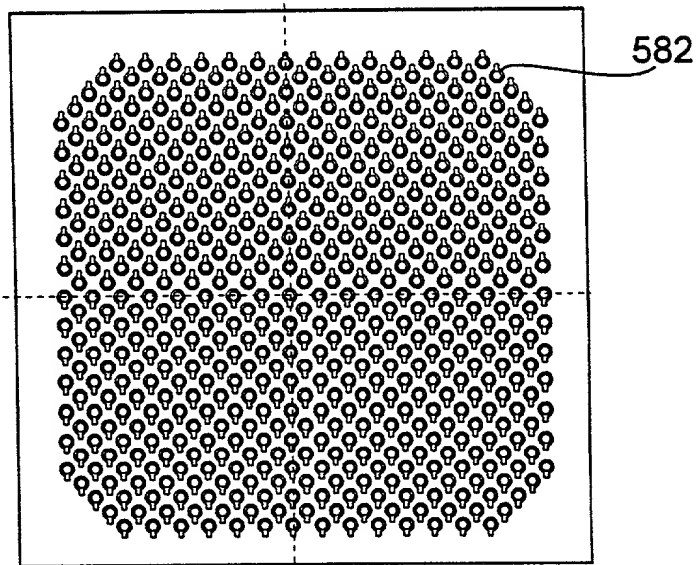
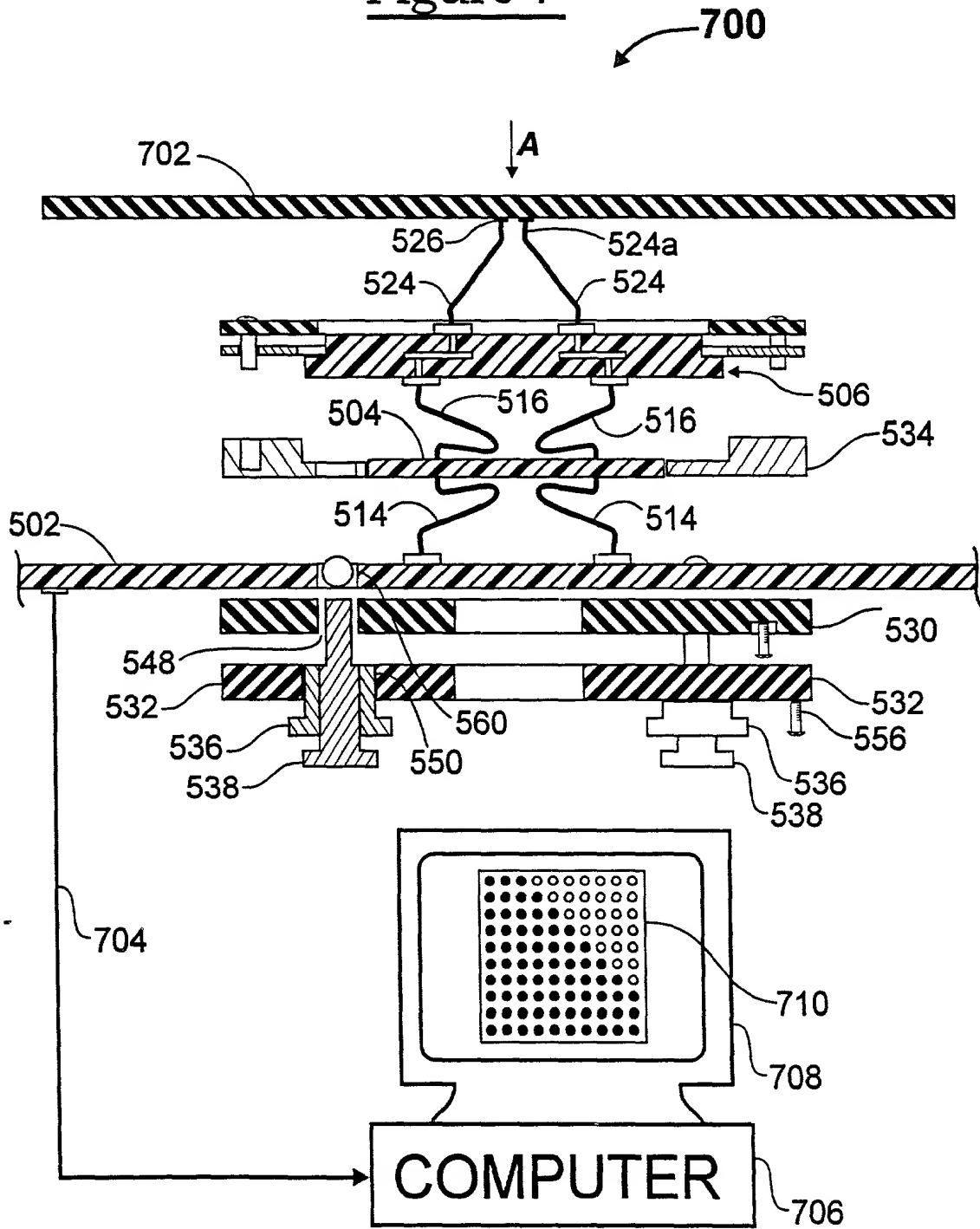


Figure 6B

580

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Figure 7



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Figure 7A

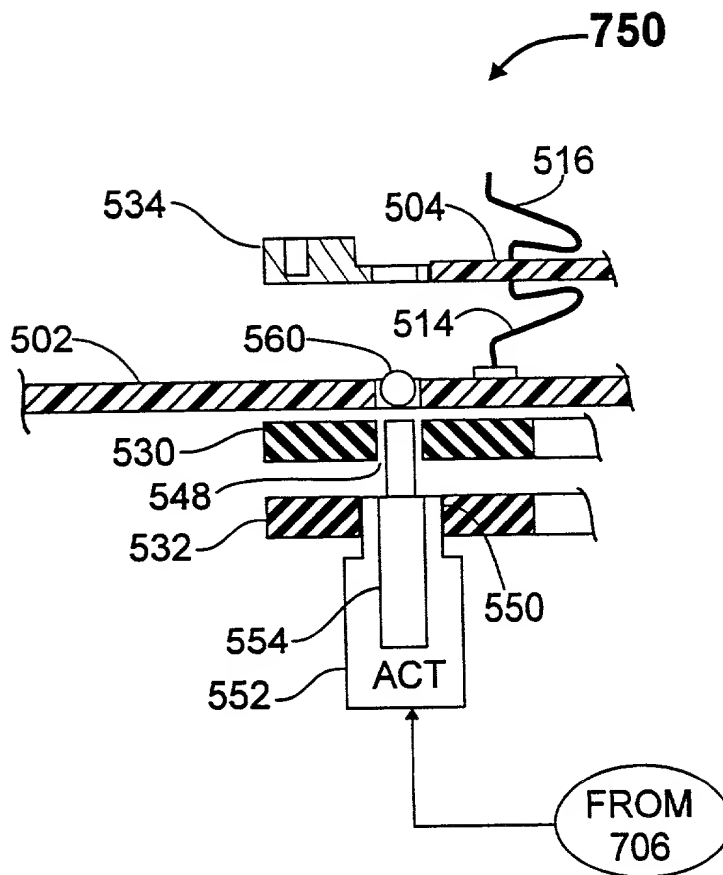


FIG. 10-06734250

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Figure 8A

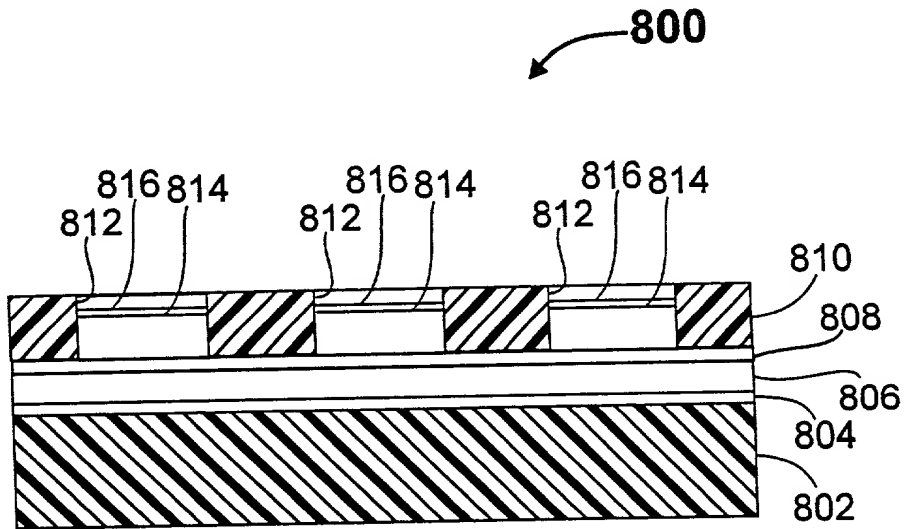
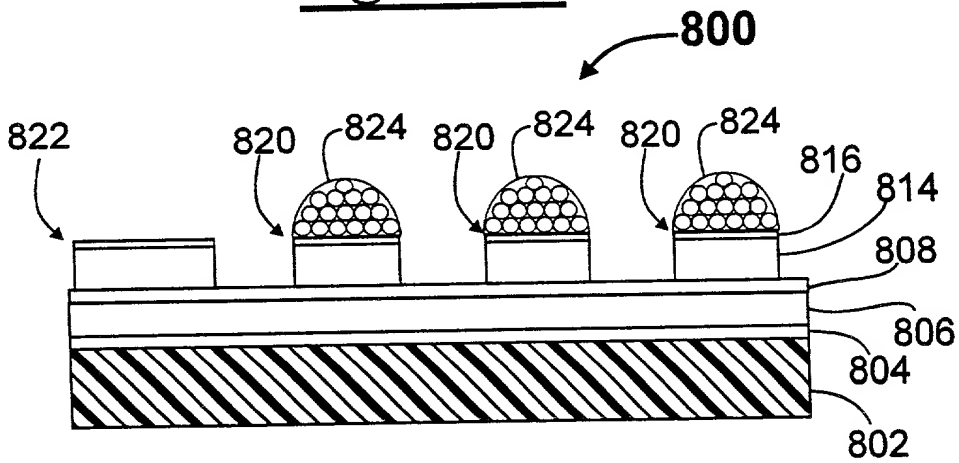


Figure 8B



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Figure 8C

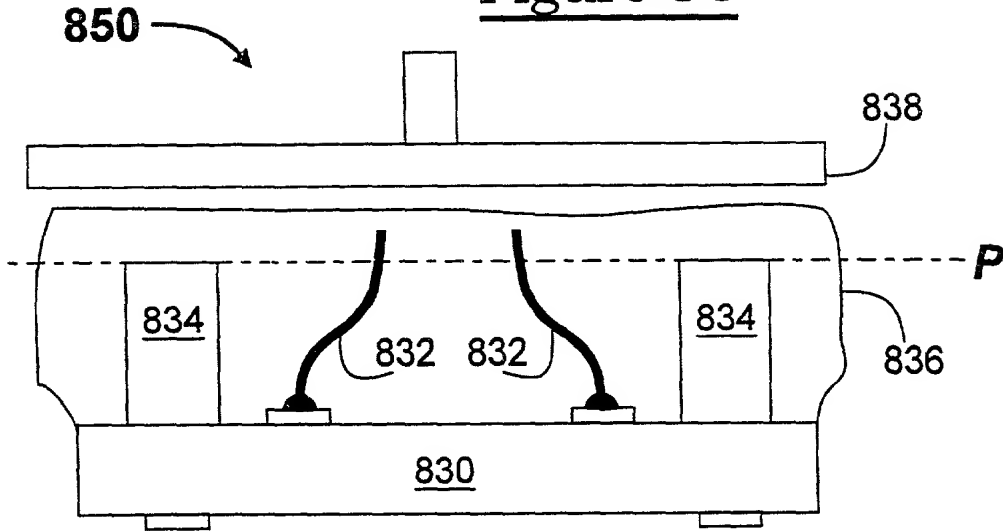


Figure 8D

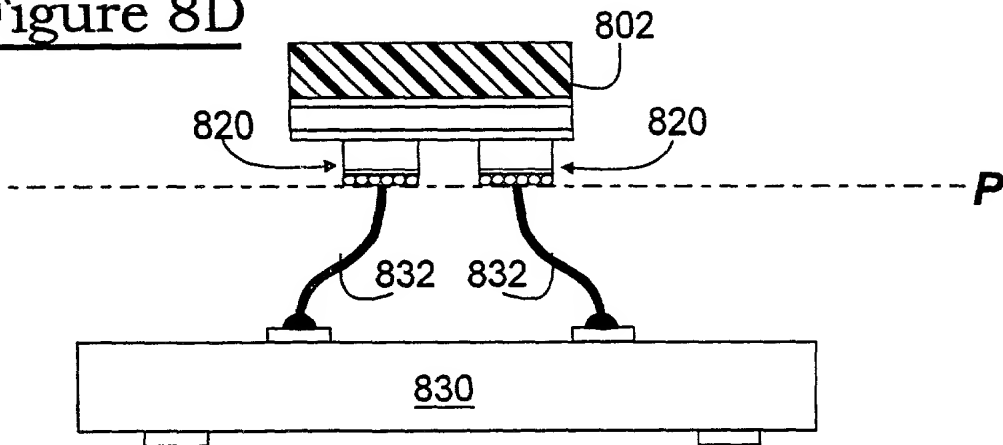


Figure 8E

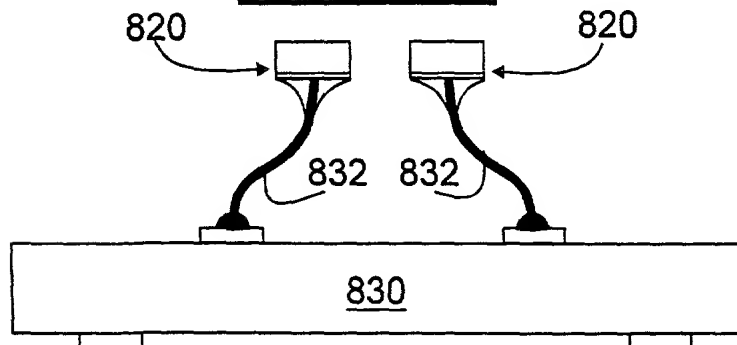


FIG. 8C